

MARCH 1975
DIGITAL 8000 SERIES TTL MEMORY

DESCRIPTION

The 93415A and 93425A are high speed 1024-bit random access memories organized as 1024 words X 1 bit. With a typical access time of 30ns, they are ideal for cache buffer applications and for systems requiring very high speed main memory.

Both the 93415A and 93425A require a single +5 volts power supply and feature very low current PNP input structures. They are fully TTL compatible, and include on-chip decoding and a chip enable input for ease of memory expansion. They feature either Open Collector or Tri-State outputs for optimization of word expansion in bussed organizations.

Both 93415A and 93425A devices are available in the commercial temperature range (0°C to +75°C).

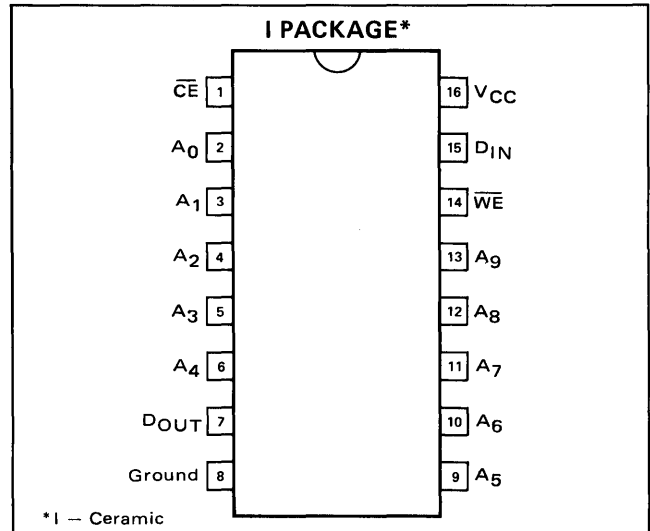
FEATURES

- ORGANIZATION – 1024 X 1
- ADDRESS ACCESS TIME – 45ns, MAXIMUM
- WRITE CYCLE TIME – 45ns, MAXIMUM
- POWER DISSIPATION – 0.5mW/BIT, TYPICAL
- INPUT LOADING – (-100µA) MAXIMUM
- ON-CHIP ADDRESS DECODING
- OUTPUT OPTIONS:
93415A – OPEN COLLECTOR
93425A – TRI-STATE
- NON-INVERTING OUTPUT
- BLANKED OUTPUT DURING WRITE
- 16 PIN CERAMIC PACKAGE

APPLICATIONS

HIGH SPEED MAIN FRAME
CACHE MEMORY
BUFFER STORAGE
WRITABLE CONTROL STORE

PIN CONFIGURATION

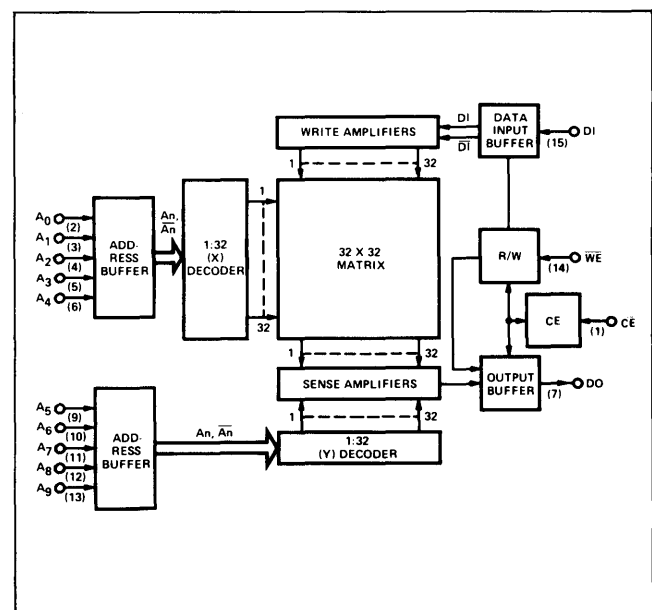


TRUTH TABLE

MODE	CE	WE	DIN	DOUT	
				93415A	93425A
READ	0	1	X	STORED DATA	STORED DATA
WRITE "0"	0	0	0	1	High-Z
WRITE "1"	0	0	1	1	High-Z
DISABLED	1	X	X	1	High-Z

X = Don't care.

BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS

PARAMETER ¹	RATING	UNIT
V _{CC} Power Supply Voltage	+7	Vdc
V _{in} Input Voltage	+5.5	Vdc
V _{OH} High Level Output Voltage (93415A)	+5.5	Vdc
V _O Off-State Output Voltage (93425A)	+5.5	Vdc
T _A Operating Temperature Range	0° to +75°	°C
T _{stg} Storage Temperature Range	-65° to +150°	°C

ELECTRICAL CHARACTERISTICS 0°C ≤ T_A ≤ +75°C, 4.75V ≤ V_{CC} ≤ 5.25

PARAMETER	TEST CONDITIONS	93415A/93425A			UNIT
		MIN	TYP ²	MAX	
V _{IL} Low Level Input Voltage	V _{CC} = MIN (Note 1)			.85	V
V _{IH} High Level Input Voltage	V _{CC} = MAX (Note 1)	2.1			V
V _{IC} Input Clamp Voltage	V _{CC} = MIN, I _{IN} = -12mA (Note 1, 7)		-1.0	-1.5	V
V _{OL} Low Level Output Voltage	V _{CC} = MIN, I _{OL} = 16mA (Note 1, 8)		0.35	0.45	V
V _{OH} High Level Output Voltage (93425A)	V _{CC} = MIN, I _{OH} = -2mA (Note 1, 5)	2.4			V
I _{OLK} Output Leakage Current (93415A)	V _{CC} = MAX, V _{OUT} = 5.5V (Note 6)		1	40	μA
I _{O(OFF)} Hi-Z State Output Current (93425A)	V _{CC} = MAX, V _{OUT} = 5.5V V _{CC} = MAX, V _{OUT} = 0.45V (Note 6)		1 -1	60 -60	μA μA
I _{IL} Low Level Input Current	V _{IN} = 0.45V		-10	-100	μA
I _{IH} High Level Input Current	V _{IN} = 5.5V		1	25	μA
I _{OS} Short Circuit Output Current (93425A)	V _{CC} = MAX, V _{OUT} = 0V (Note 3)	-20		-100	mA
I _{CC} V _{CC} Supply Current	V _{CC} = MAX (Note 4) 0 < T _A < 25°C T _A ≥ 25°C T _A ≤ 0°C		120 95	155 130 170	mA mA mA
C _{IN} Input Capacitance	V _{CC} = 5.0V, V _{IN} = 2.0V		4		pF
C _{OUT} Output Capacitance	V _{CC} = 5.0V, V _{OUT} = 2.0V		7		pF

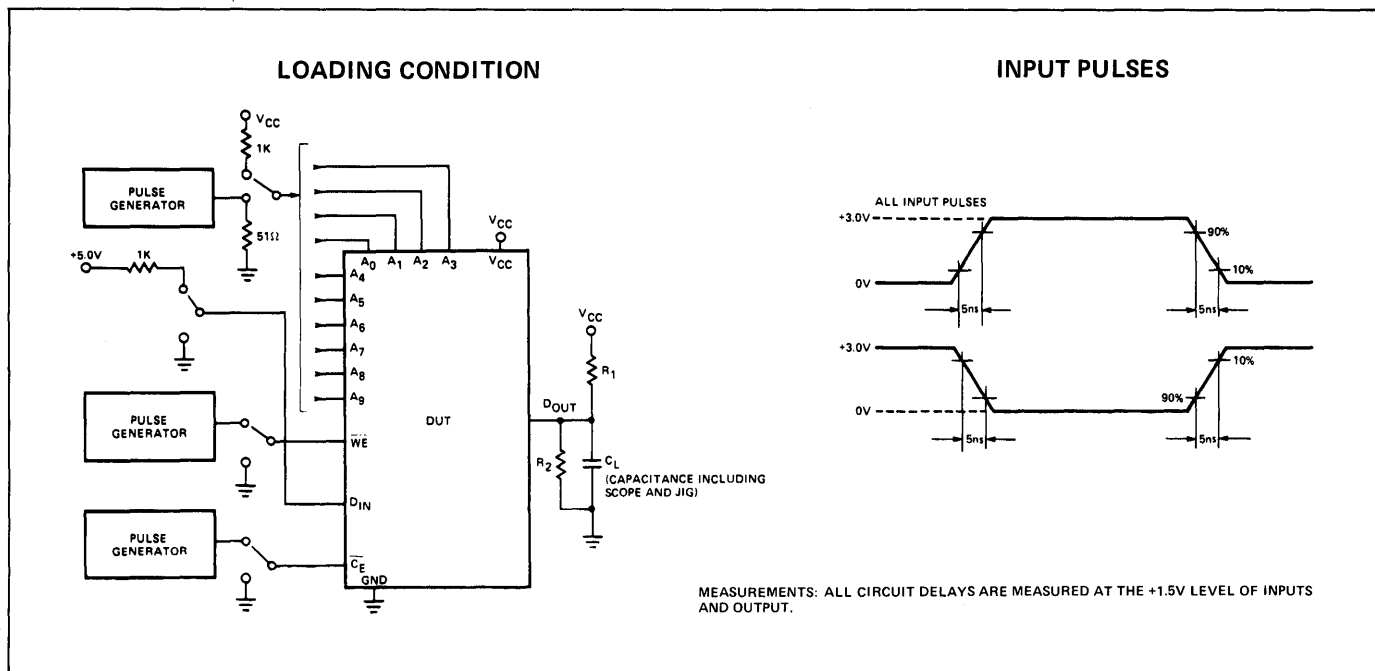
NOTES:

- All voltage values are with respect to network ground terminal.
- All typical values are at V_{CC} = 5V, T_A = 25°C.
- Duration of the short-circuit should not exceed one second.
- I_{CC} is measured with the write enable and memory enable inputs grounded, all other inputs at 4.5V, and the output open.
- Measured with V_{IL} applied to \overline{CE} and a logic "1" stored.
- Measured with V_{IH} applied to \overline{CE} .
- Test each input one at the time.
- Measured with a logic "0" stored. Output sink current is supplied through a resistor to V_{CC}.
- The Operating Ambient Temperature Ranges are guaranteed with transverse air flow exceeding 400 linear feet per minute and a two minute warm-up. Typical thermal resistance values of the package at maximum temperature are:
 - φ_{JA} Junction to Ambient at 400 fpm air flow - 50°C/Watt
 - φ_{JA} Junction to Ambient - still air - 90°C/Watt
 - φ_{JA} Junction to Case - 20°C/Watt

SWITCHING CHARACTERISTICS³ 0°C ≤ T_A ≤ +75°C, 4.75V ≤ V_{CC} ≤ 5.25

PARAMETER	TEST CONDITIONS	93415A/93425A			UNIT
		MIN	TYP ¹	MAX	
Propagation Delays					
T _{AA} Address Access Time			30	45	ns
T _{CE} Chip Enable Access Time			15	30	ns
T _{CD} Chip Enable Output Disable Time			15	30	ns
T _{WD} Write Enable to Output Disable Time			20	30	ns
T _{WR} Write Recovery Time			20	30	ns
Write Set-up Times					
T _{WSA} Address to Write Enable	C _L = 30pF R ₁ = 270Ω	5	0		ns
T _{WSD} Data In to Write Enable	R ₂ = 600Ω	40	35		ns
T _{WSC} \overline{CE} to Write Enable		5	0		ns
Write Hold Times					
T _{WHA} Address to Write Enable		5	0		ns
T _{WHD} Data In to Write Enable		5	0		ns
T _{WHC} \overline{CE} to Write Enable		5	0		ns
T _{WP} Write Enable Pulse Width (Note 2)		35	25		ns

AC TEST LOAD

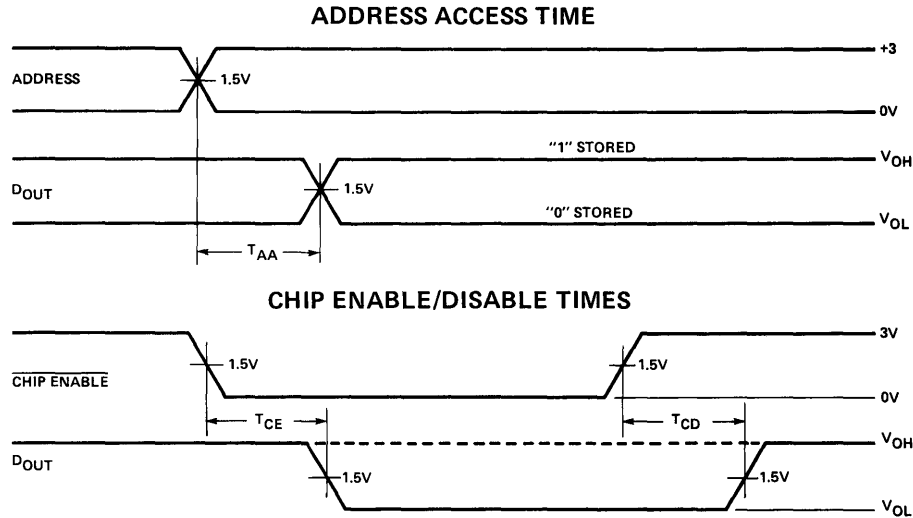


NOTES:

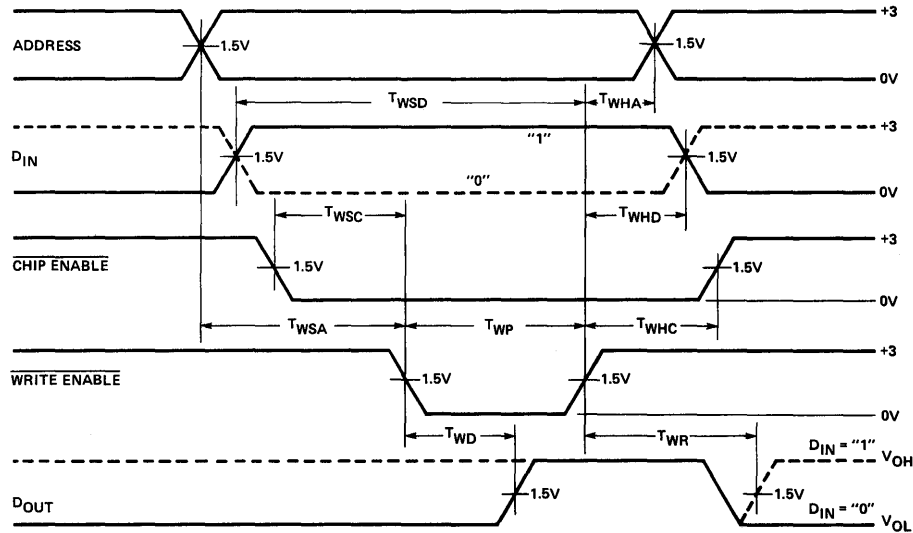
1. Typical values are at V_{CC} = +5.0V, and T_A = +25°C.
2. Minimum required to guarantee a WRITE into the slowest bit.
3. The Operating Ambient Temperature Ranges are guaranteed with transverse air flow exceeding 400 linear feet per minute and a two minute warm-up. Typical thermal resistance values of the package at maximum temperature are:
 θ_{JA} Junction to Ambient at 400 fpm air flow – 50°C/Watt
 θ_{JA} Junction to Ambient – still air – 90°C/Watt
 θ_{JA} Junction to Case – 20°C/Watt

SWITCHING PARAMETERS MEASUREMENT INFORMATION

READ CYCLE



WRITE CYCLE

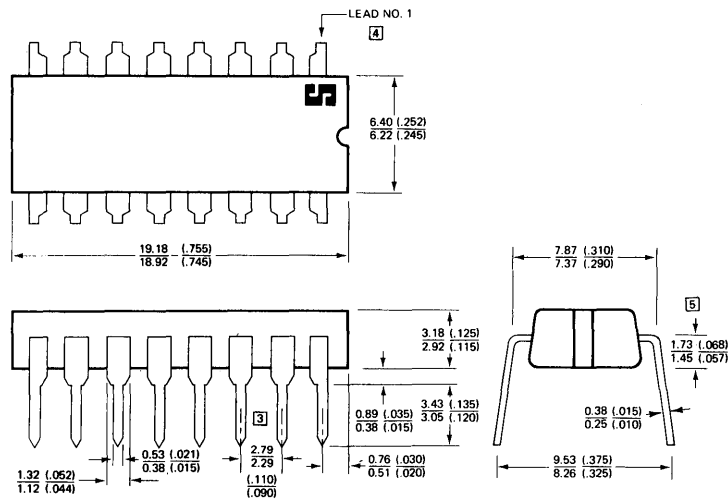


MEMORY TIMING DEFINITIONS

<p>T_{WR} Delay between end of WRITE ENABLE pulse and when DATA OUTPUT becomes valid. (Assuming ADDRESS still valid—not as shown.)</p> <p>T_{CE} Delay between beginning of CHIP ENABLE low (with ADDRESS valid) and when DATA OUTPUT becomes valid.</p> <p>T_{CD} Delay between when CHIP ENABLE becomes high and DATA OUTPUT is in off state.</p> <p>T_{AA} Delay between beginning of valid ADDRESS (with CHIP ENABLE low) and when DATA OUTPUT becomes valid.</p> <p>T_{WSC} Required delay between beginning of valid CHIP ENABLE and beginning of WRITE ENABLE pulse.</p>	<p>T_{WHD} Required delay between end of WRITE ENABLE pulse and end of valid INPUT DATA.</p> <p>T_{WP} Width of WRITE ENABLE pulse.</p> <p>T_{WSA} Required delay between beginning of valid ADDRESS and beginning of WRITE ENABLE pulse.</p> <p>T_{WSD} Required delay between beginning of valid DATA INPUT and end of WRITE ENABLE pulse.</p> <p>T_{WD} Delay between beginning of WRITE ENABLE pulse and when DATA OUTPUT is in off state.</p> <p>T_{WHC} Required delay between end of WRITE ENABLE pulse and end of CHIP ENABLE.</p> <p>T_{WHA} Required delay between end of WRITE ENABLE pulse and end of valid ADDRESS.</p>
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SIGNETICS PACKAGES

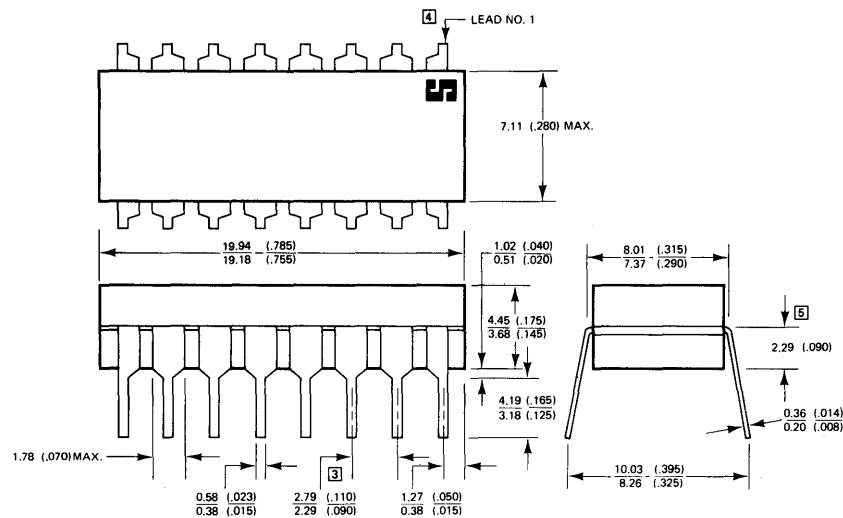
B PACKAGE



NOTES:

1. Lead Material: Alloy 42 or equivalent.
2. Body Material: Plastic.
3. Tolerances non cumulative.
4. Signetics symbol denotes Lead No. 1.
5. Lead spacing shall be measured within this zone.
6. Body dimensions do not include molding flash.
7. Thermal Resistance: $\Theta_{Ja} = .16^{\circ}\text{C/mW}$, $\Theta_{Jc} = .08^{\circ}\text{C/mW}$.
8. All dimensions shown in parentheses are English. (Inches)

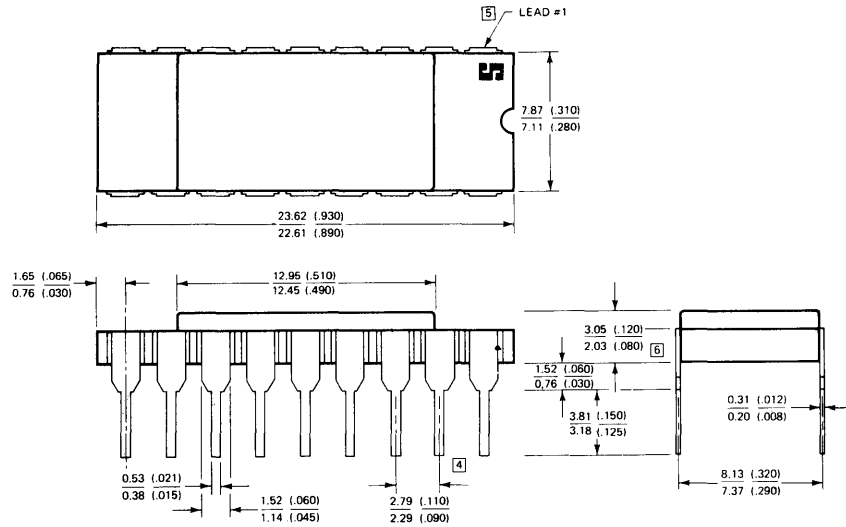
FJ PACKAGE



NOTES:

1. Lead material: Alloy 42 or equivalent, tin plated.
2. Body material: Ceramic with glass seal.
3. Tolerances non cumulative.
4. Signetics symbol denotes Lead No. 1.
5. Lead spacing shall be measured within this zone.
6. Thermal resistance: $\Theta_{Ja} = .090^{\circ}\text{C/mW}$, $\Theta_{Jc} = .025^{\circ}\text{C/mW}$.
7. All dimensions shown in parentheses are English. (Inches)

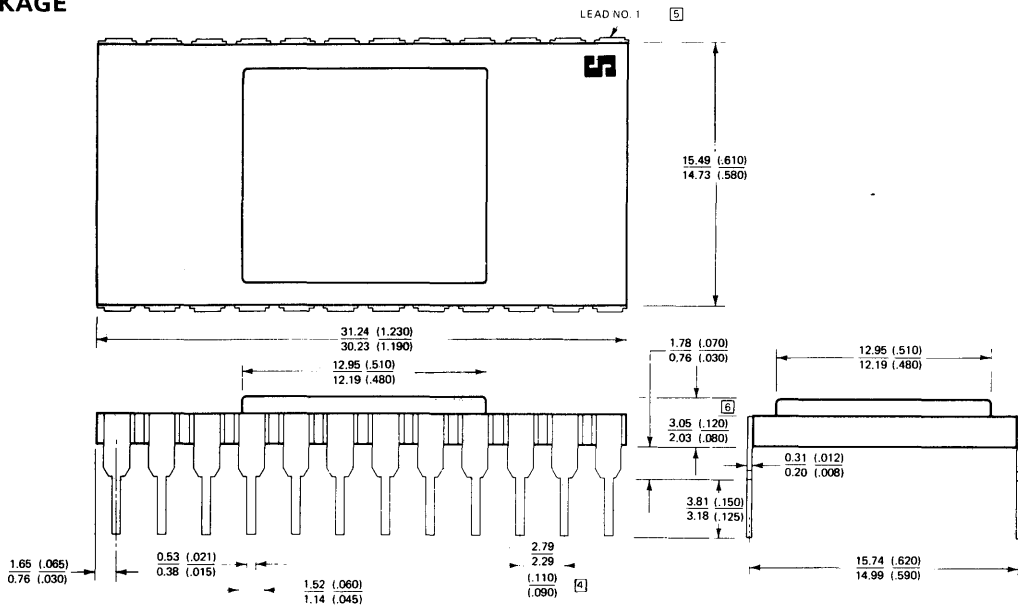
IJA PACKAGE



NOTES:

- Lead material: Kovar or equivalent, tin plated.
- Body material: Ceramic with Kovar or equivalent.
- Lid material: Ceramic, glass seal.
- Tolerances non cumulative.
- Signetics symbol denotes Lead No. 1.
- Lead spacing shall be measured within this zone.
- Thermal resistance: $\Theta_{Ja} = .080^{\circ}\text{C}/\text{mW}$, $\Theta_{Jc} = .020^{\circ}\text{C}/\text{mW}$.
- All dimensions shown in parentheses are English. (Inches)

INB PACKAGE

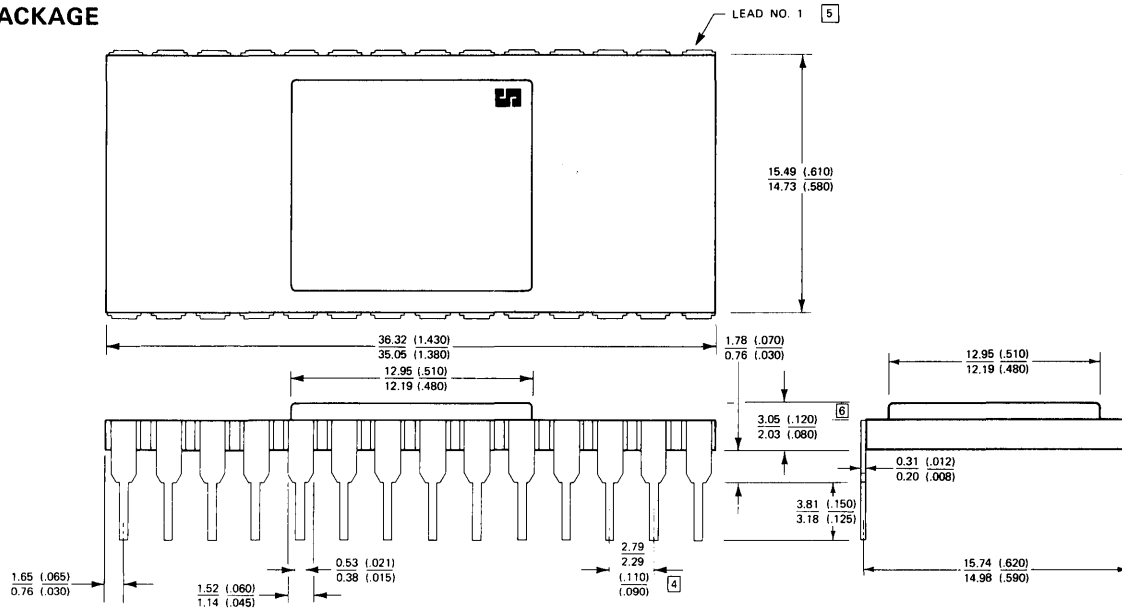


NOTES:

- Lead material: Kovar or equivalent, gold plated.
- Body material: Ceramic with Kovar or equivalent.
- Lid material: Kovar or equivalent, gold plated, alloy seal.
- Tolerances non cumulative.
- Signetics symbol denotes Lead No. 1.
- Lead spacing shall be measured within this zone.
- Thermal resistance: $\Theta_{Ja} = .050^{\circ}\text{C}/\text{mW}$, $\Theta_{Jc} = .015^{\circ}\text{C}/\text{mW}$.
- All dimensions shown in parentheses are English. (Inches)

SIGNETICS PACKAGES

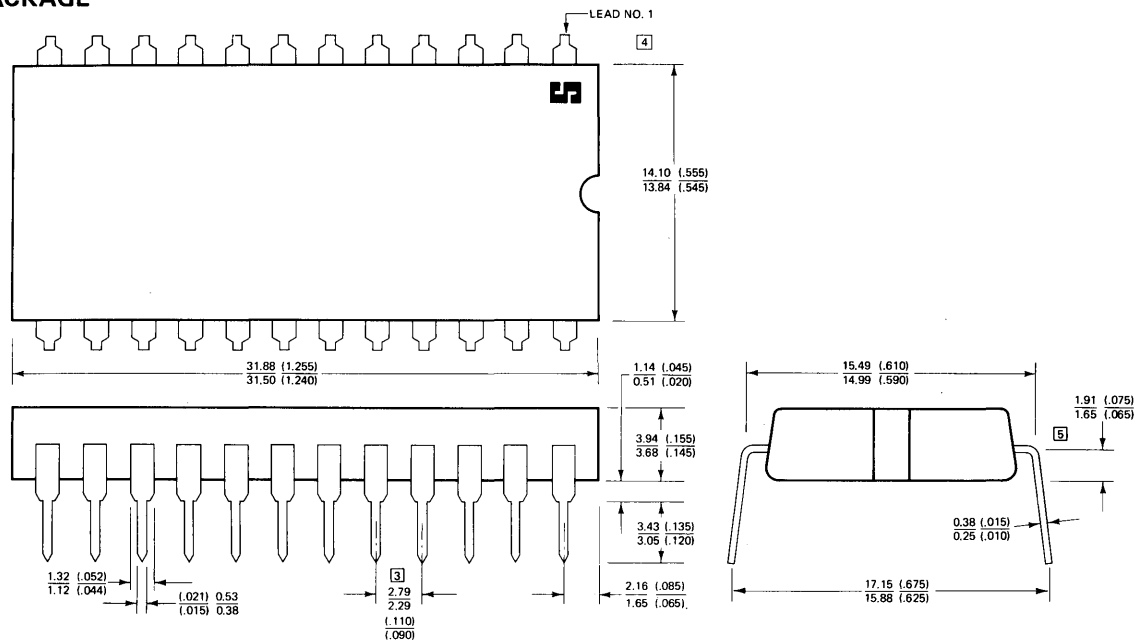
IQ PACKAGE



NOTES:

1. Lead material: Kovar or equivalent, tin plated.
2. Body material: Ceramic with Kovar or equivalent.
3. Lid material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Signetics symbol denotes Lead No. 1.
6. Lead spacing shall be measured within this zone.
7. Thermal resistance: $\Theta_{Ja} = .050^{\circ}\text{C/mW}$, $\Theta_{Jc} = .010^{\circ}\text{C/mW}$.
8. All dimensions shown in parentheses are English. (Inches)

N PACKAGE



NOTES:

1. Lead Material: Alloy 42 or equivalent.
2. Body Material: Plastic
3. Tolerances non cumulative.
4. Signetics symbol denotes Lead No. 1.
5. Lead spacing shall be measured within this zone.
6. Body dimensions do not include molding flash.
7. Thermal Resistance: $\Theta_{Ja} = .12^{\circ}\text{C/mW}$, $\Theta_{Jc} = .05^{\circ}\text{C/mW}$.
8. All dimensions shown in parentheses are English. (Inches)